

ADDITIONS AND CORRECTIONS

1999, Volume 103

Y. Gu, B. Akhremitchev, G. C. Walker, and D. H. Waldeck*: Structural Characterization and Electron Tunneling at *n*-Si/SiO₂/SAM/Liquid Interface

Page 5220. The following section was omitted from the above article.

Supporting Information Available: Two figures that display the four regions imaged in the AFM studies and an expanded view of the islands in the partially coated region. This material is available free of charge via the Internet at <http://pubs.acs.org>.

10.1021/jp991908i

Published on Web 06/16/1999